

New Methods for the Optical Design of Spectrometers with Freeform Surfaces

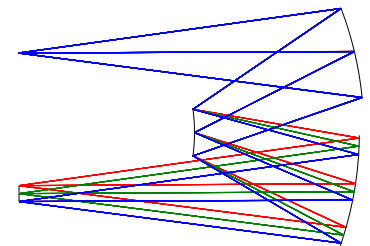
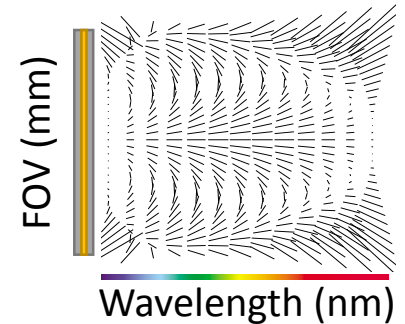
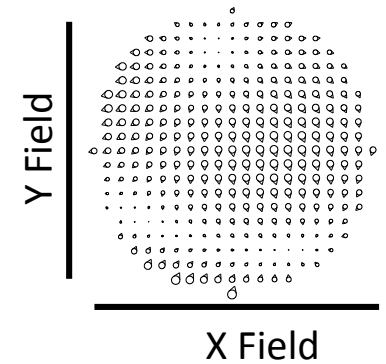
Jacob Reimers, Kevin P. Thompson,
Kevin L. Whiteaker, and Jannick P. Rolland

Center for Freeform Optics (CeFO)

The Institute of Optics, University of Rochester
Ball Aerospace

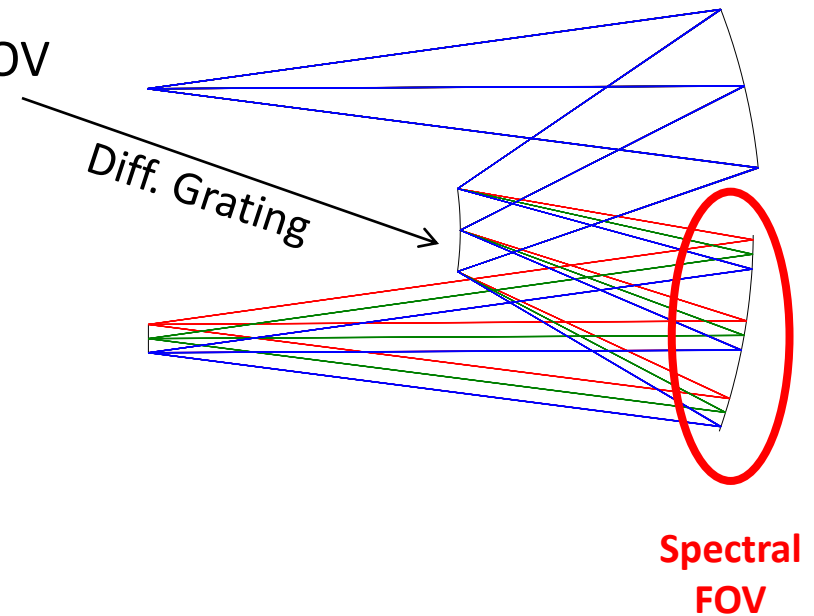
Outline

- Introduction
- Design tools for freeform surfaces
- Spectral full-field display
- Freeform spectrometer design example
- Conclusion



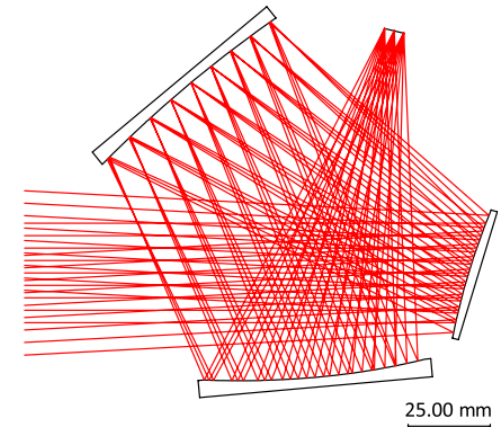
Introduction

- Designing pushbroom imaging spectrometers is challenging
 - Slit field of view (FOV)
 - Dispersive element creates spectral FOV
 - Often coupled with foreoptics

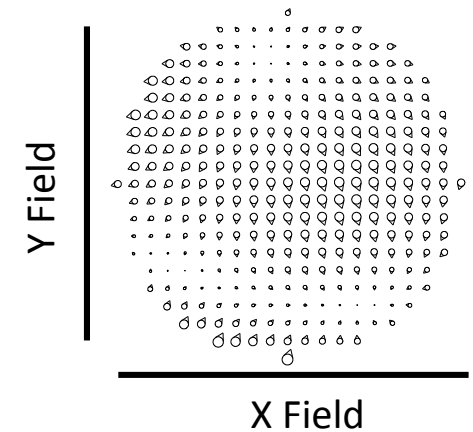


Design tools for freeform systems

- The full-field display (FFD) has been successfully utilized in the design of a LWIR freeform imager
- In the context of spectrometer design, this requires a new, spectral, full-field display (**SFFD**) to be developed
- The SFFD will enable the aberration visualization and guide the design of freeform spectrometers



LWIR imager



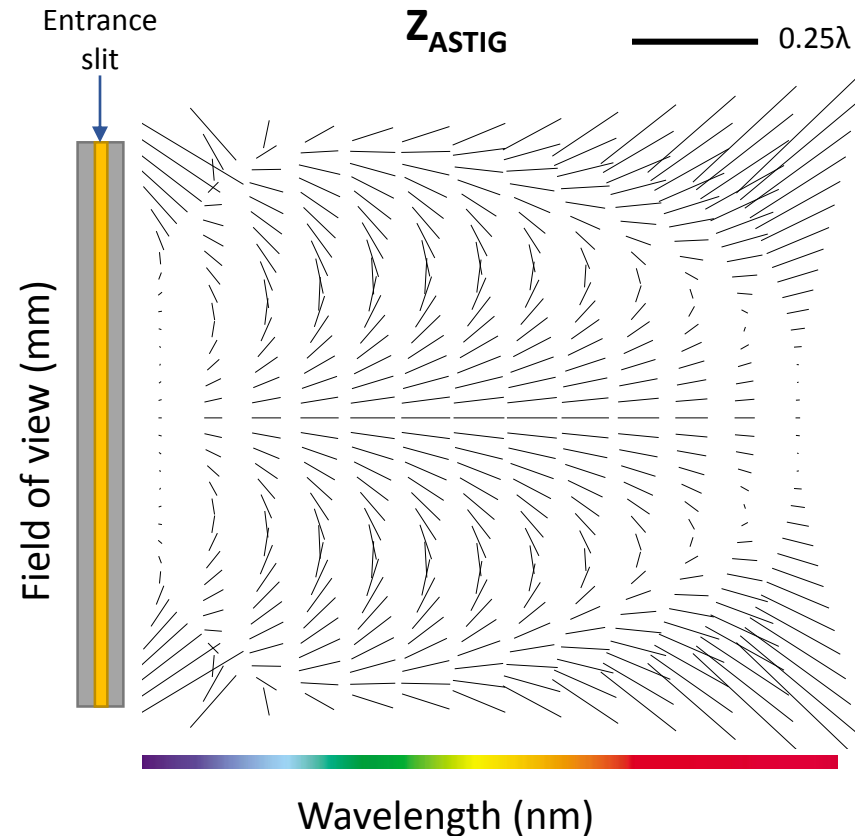
Full-field display

K. Fuerschbach, J. Rolland, and K. Rolland-Thompson, "Realizing Freeform: A LWIR Imager in a Spherical Package," in Renewable Energy and the Environment, OSA Technical Digest (online) (Optical Society of America, 2013), paper FW1B.2.

Spectral full-field display (SFFD)

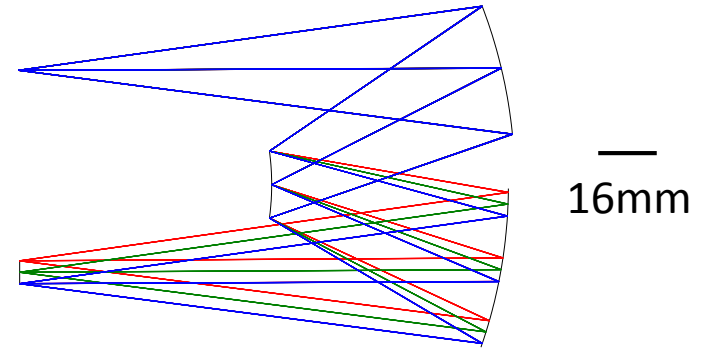
A new type of visualization for dispersive imaging systems that is:

- A plot of Fringe Zernike coefficients on field of view vs. wavelength
- Calculated on a term-by-term basis using real ray trace calculations

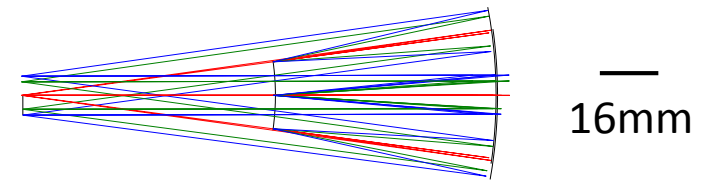


Design example using freeform optics

- Specifications:
 - F/3.8
 - 200-1500 nm spectral bandwidth
 - 10mm entrance slit length
 - 100nm/mm dispersion
- Offner-Chrisp (OC) spectrometer
 - Concentric
 - Corrects spherical aberration
 - 1-1 magnification
 - Corrects coma and distortion
 - Limited by astigmatism
 - Ring field balance



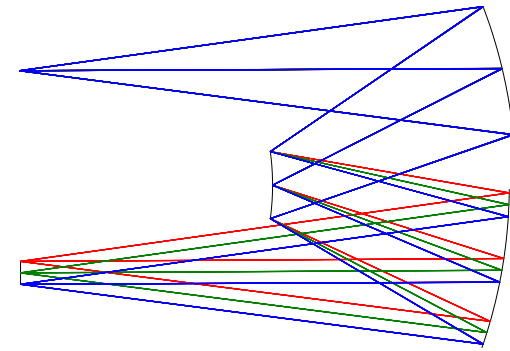
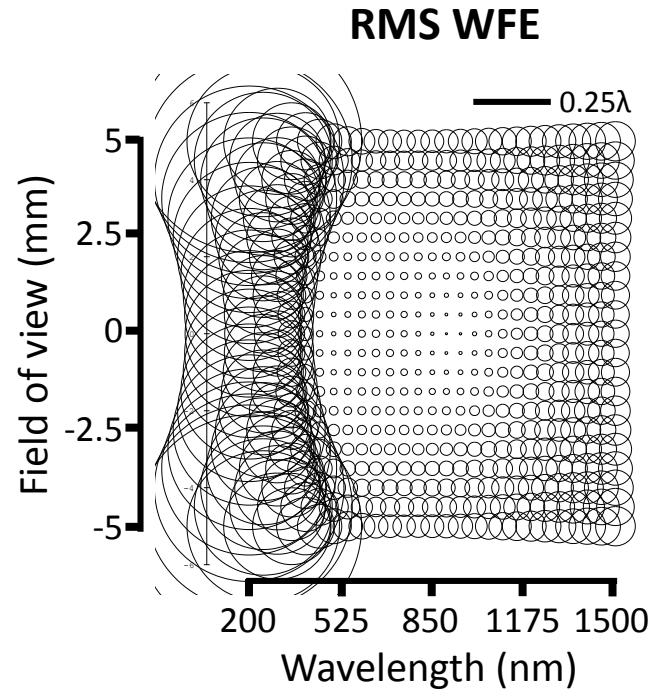
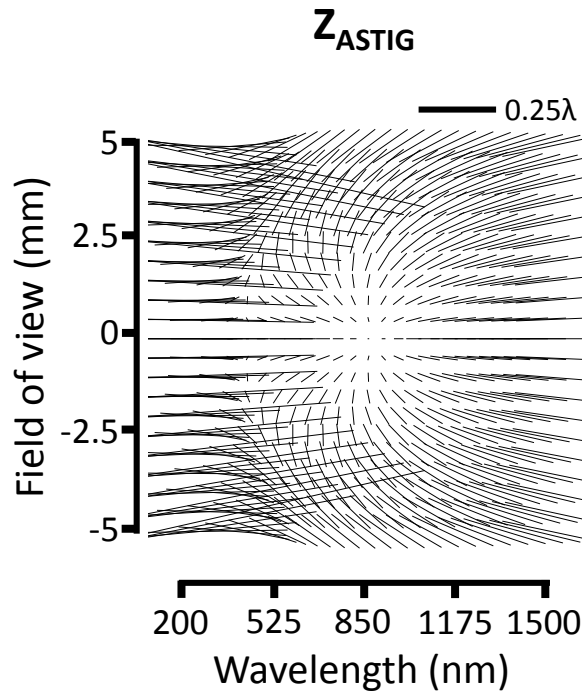
YZ (dispersion) plane



XZ (slit/field) plane

M. Chrisp, "Convex diffraction grating imaging spectrometer,"
US Pat. 5,880,834 (1999).

OC spectrometer - All spherical performance



The maximum/average RMS WFE was calculated for all fields and wavelengths for comparison

All spherical surfaces:

Max RMS WFE: **0.731λ**

Avg. RMS WFE: **0.097λ**

Benchmarking with coaxial aspheres

All surfaces aspheric (A-D):

Max RMS WFE: 0.427λ
 Avg. RMS WFE: 0.091λ



All aspheric surfaces with astigmatic node shift:

Max RMS WFE: 0.205λ
 Avg. RMS WFE: 0.096λ



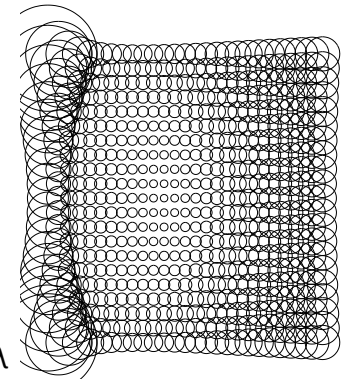
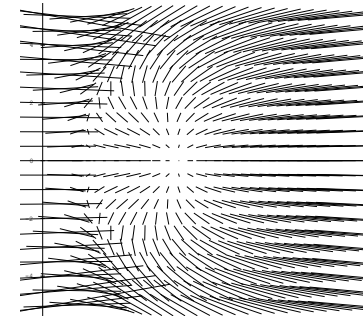
Anamorphic aspheric surfaces:

Max RMS WFE: 0.186λ
 Avg. RMS WFE: 0.092λ

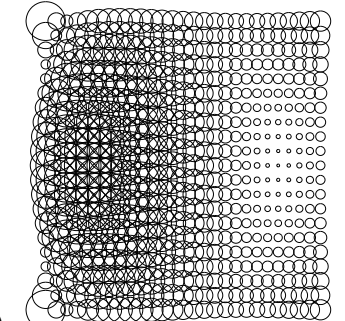
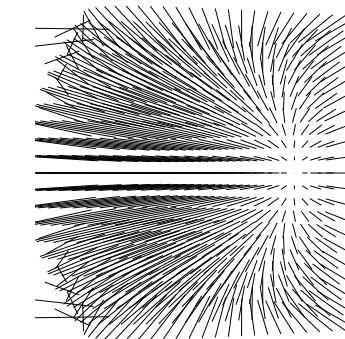


Z_{ASTIG}

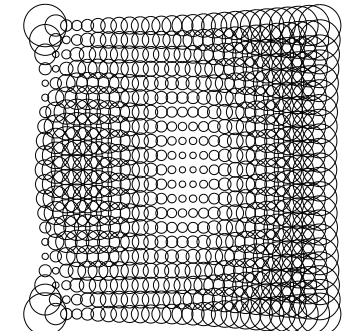
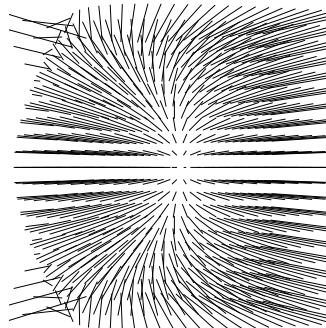
RMS WFE



0.25λ



0.25λ



Benchmarking with coaxial aspheres

All surfaces aspheric (A-D):

Max RMS WFE: 0.427λ
 Avg. RMS WFE: 0.091λ



All aspheric surfaces with astigmatic node shift:

Max RMS WFE: 0.205λ
 Avg. RMS WFE: 0.096λ

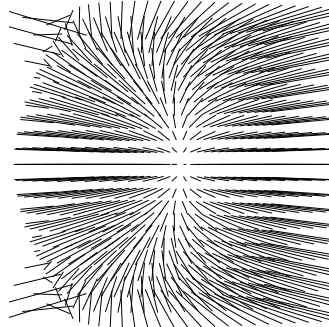
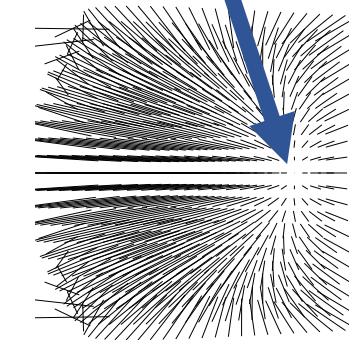
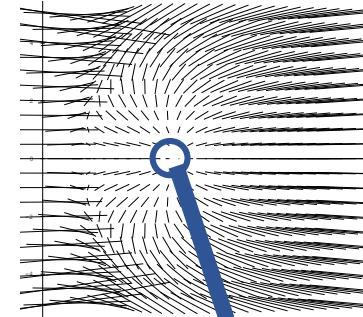


Anamorphic aspheric surfaces:

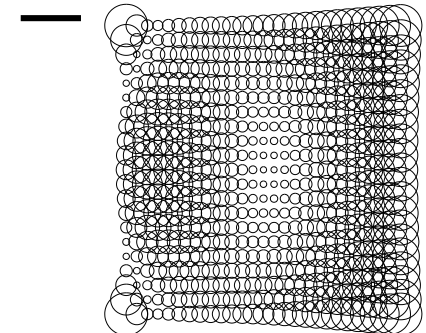
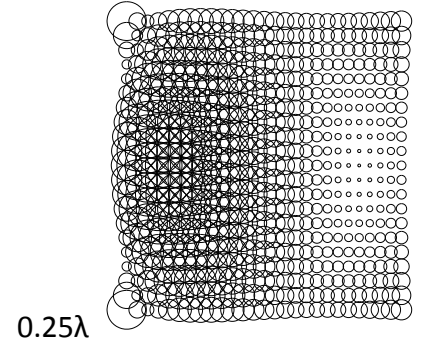
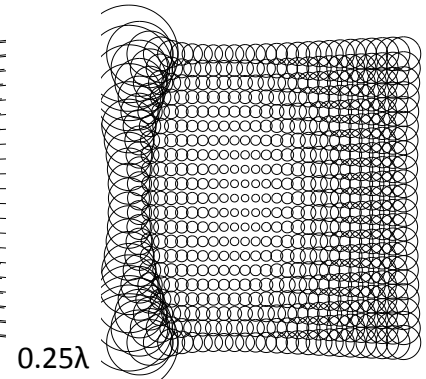
Max RMS WFE: 0.186λ
 Avg. RMS WFE: 0.092λ



Z_{ASTIG}

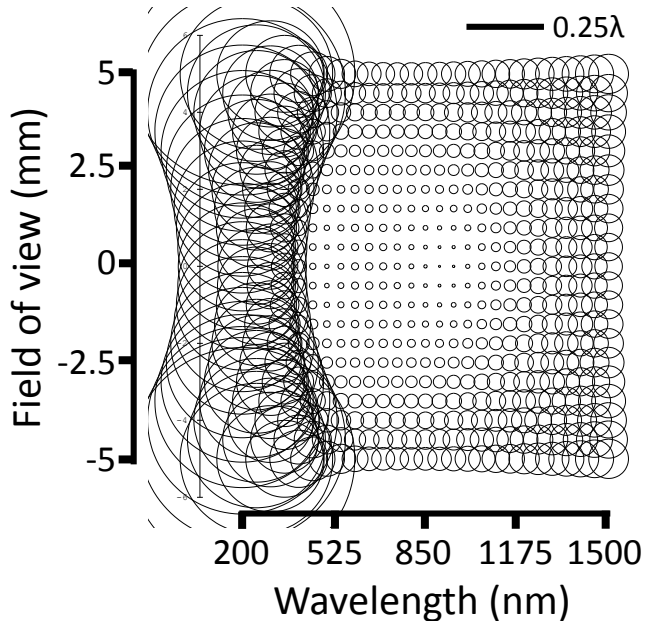


RMS WFE



Summary of benchmarking aspheres

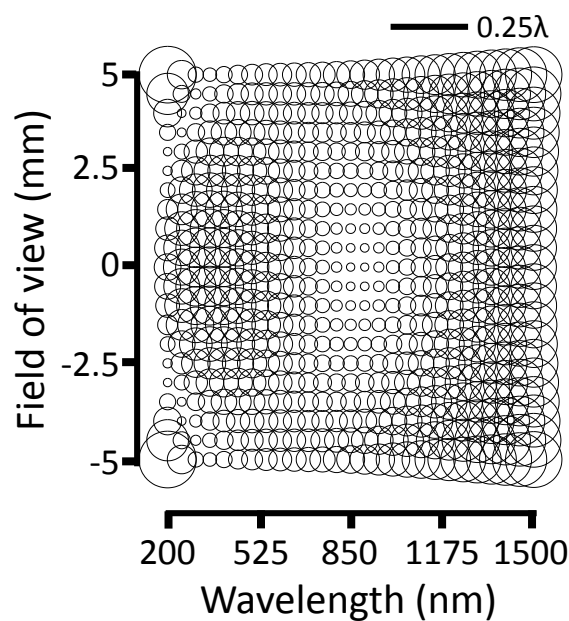
RMS WFE



All spherical surfaces:

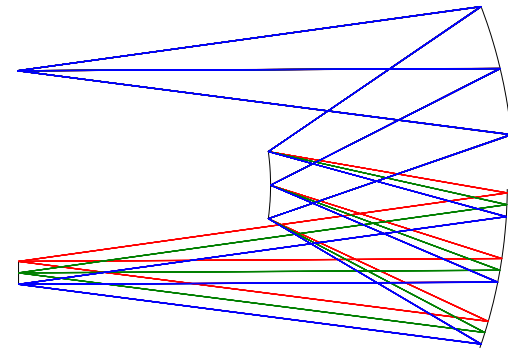
Max RMS WFE: 0.731λ
 Avg. RMS WFE: 0.097λ

RMS WFE



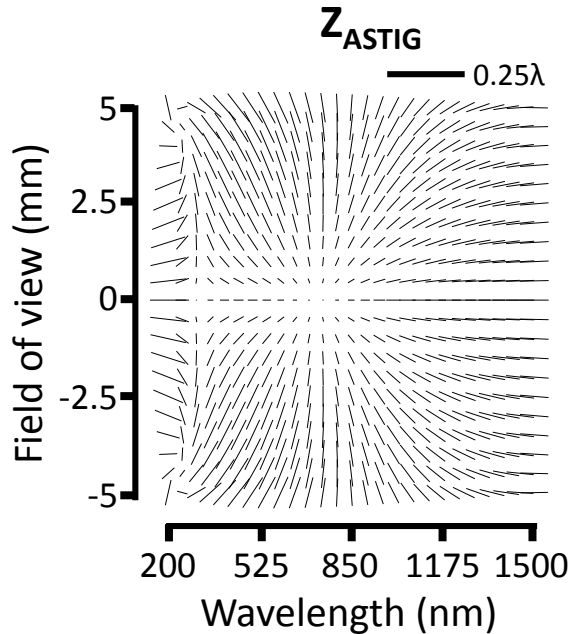
Anamorphic asphere:

Max RMS WFE: 0.186λ
 Avg. RMS WFE: 0.092λ



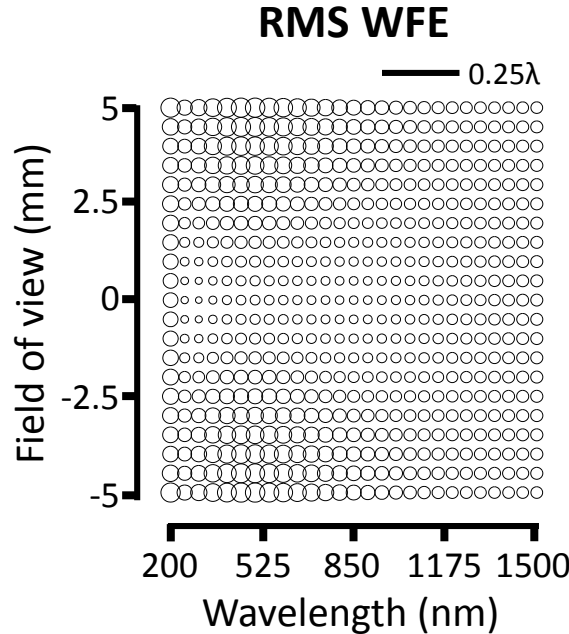
Note: Avg. RMS WFE does not decrease appreciably

OC spectrometer - freeform performance



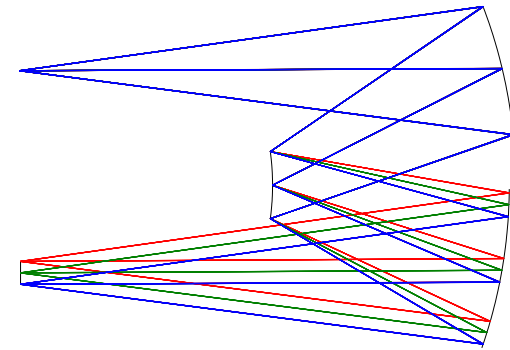
All spherical surfaces:

Max RMS WFE: **0.731λ**
Avg. RMS WFE: **0.097λ**



Anamorphic asphere:

Max RMS WFE: **0.186λ**
Avg. RMS WFE: **0.092λ**

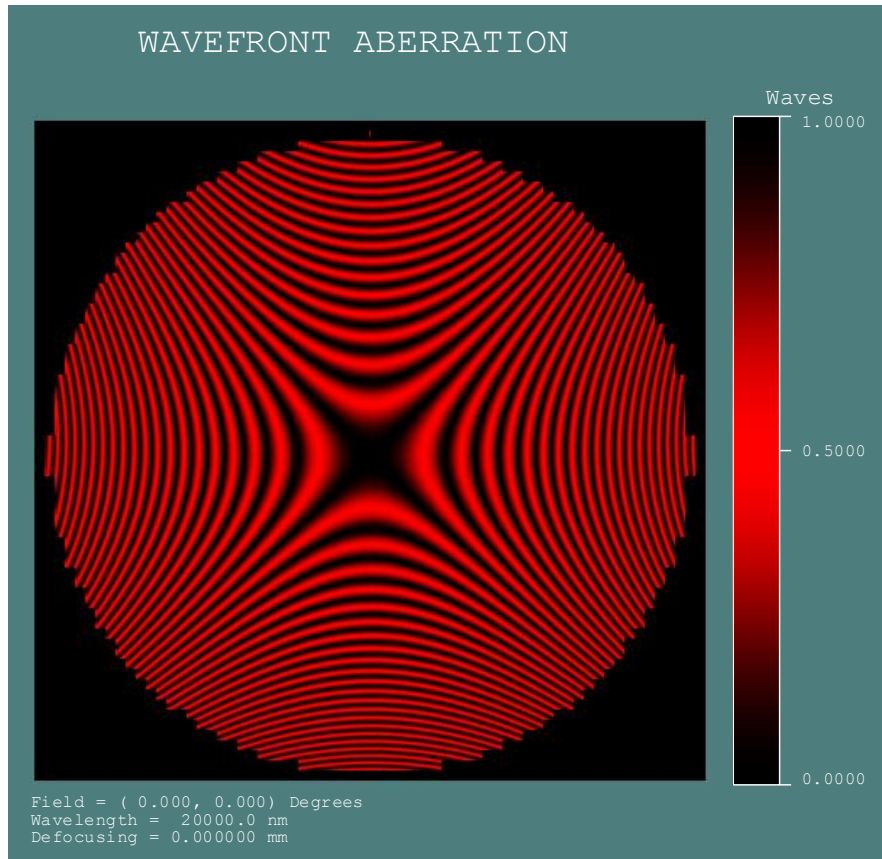


Surfaces are of the ϕ -polynomial (Fringe Zernike) type

All freeform surfaces:
Diffraction limited for all fields and wavelengths

Max RMS WFE: **0.063λ**
Avg. RMS WFE: **0.041λ**

Freeform surface departures



Tertiary – largest departure

PV 833 μm

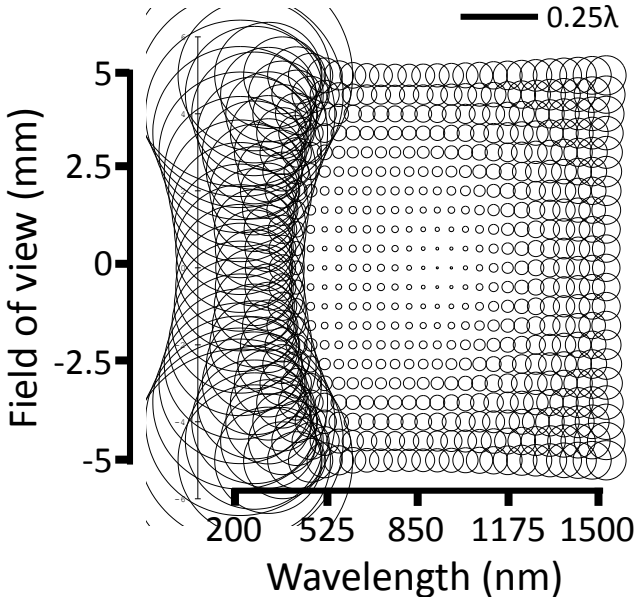
Exact shape may vary

Common to all surfaces:
Dominated by Astigmatism
< 1000 μm departure

Spherical vs. freeform OC spectrometer

RMS WFE

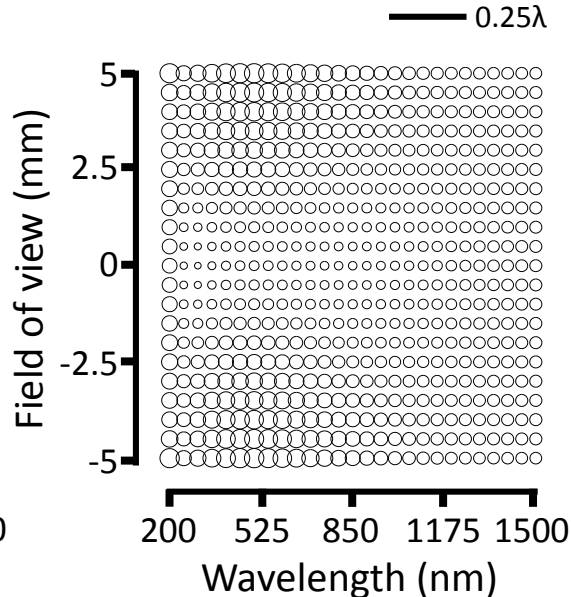
— 0.25λ



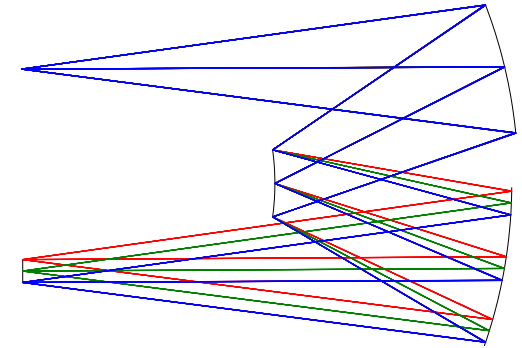
Spherical

RMS WFE

— 0.25λ



Freeform



Avg. RMS WFE:

Spherical → asphere

6% decrease

Spherical → anamorphic asphere

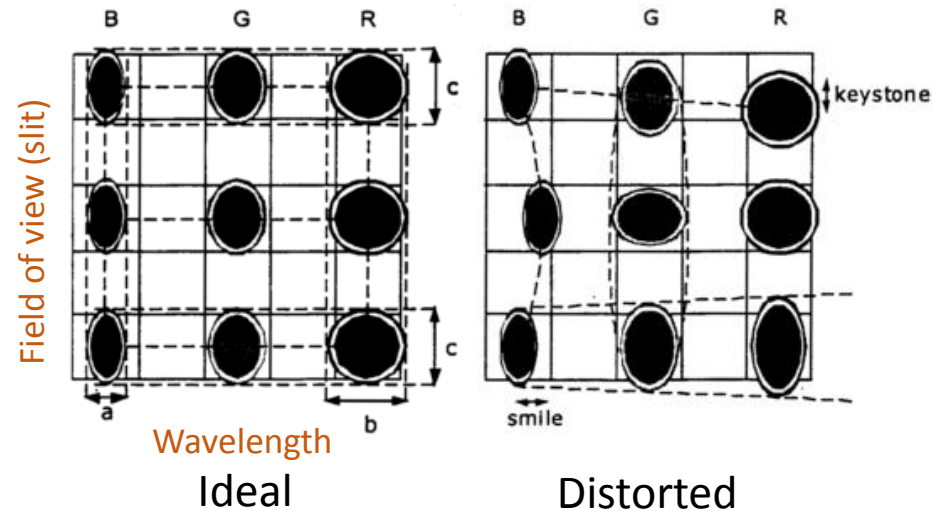
5% decrease

Spherical → freeform

58% decrease

Simultaneous achievement of optical performance and distortion correction

- Imaging spectrometers have two types of distortion
 - Spectral smile
 - Typically want to be $<1\%$ of a pixel
 - Spatial keystone
 - Typically want to be $<5\%$ of a pixel
 - Measured the deviation with respect to the centroid of each wavelength or field
- Distortion and imaging performance are a design trade-off for spectrometers consisting of all-spherical surfaces
 - Freeform corrects smile/keystone while retaining diffraction limited performance in the Offner-Chrisp



Spectral broadened Offner-Chrisp was analyzed to have max $0.1\mu\text{m}$ smile and $0.08\mu\text{m}$ keystone which for a $10\mu\text{m}$ pixel is 1% and 0.8% respectively

P. Mouroulis, R. O. Green, and T. G. Chrien, "Design of pushbroom imaging spectrometers for optimum recovery of spectroscopic and spatial information.," Appl. Opt. **39**, 2210–20 (2000).

Summary

- The SFFD calculates the magnitude and direction of Fringe Zernike coefficients and plots them on field of view vs. wavelength axes
- The SFFD assists the designer in the design of spectrometers
- Insights provided by nodal aberration theory and the SFFD motivate novel compact high performance freeform spectrometers
- The use of freeform surfaces in an Offner-Chrisp spectrometer enables a much wider spectral bandwidth than spherical or aspheric designs due to correction of the astigmatic field as seen using the SFFD
- Leveraging freeform in an Offner-Chrisp facilitates simultaneous optical performance and distortion correction

Acknowledgements

- NSF I/UCRC Center for Freeform Optics (**CeFO**)
*Ball Aerospace & Technologies Corp.; OptiPro Systems, LLC;
PerkinElmer; PolymerPlus LLC; Rochester Precision Optics; SCHOTT North
America, Inc.; Air Force Research Laboratory; Zygo Corporation; ARRI.*
- Peter Marasco and Dennis Yates for the stimulating discussions
- Synopsys Inc. for the student license of CODE V